

Application No.	Applicant(s)	
09/886,741	CHAN ET AL.	
Examiner	Art Unit	
Chris C. Chu	2815	

SEARCHED					
Class	Subclass	Date	Examiner		
257	706 and 796	11/23/2004	C.C.		
:-					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in USPAT; US-PGPUB; EPO; JPO; DERWENT; and IBM_TDB;	11/23/2004	C.C.		
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